

Docket No.: W&B-INF-908

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : JUSTUS KUHN ET AL.

Filed : CONCURRENTLY HEREWITH

Title : DEVICE AND METHOD FOR REDUCING THE NUMBER OF ADDRESSES OF FAULTY MEMORY CELLS

INFORMATION DISCLOSURE STATEMENT

Hon. Commissioner of Patents and Trademarks,
Washington, D.C. 20231

Siri

In accordance with 37 C.F.R. 1.98 copies of the following patents and/or publications are submitted herewith:

Haddad, R. et al.: "Increased Throughput for the Testing and Repair of RAM's with Redundancy", IEEE, Vol. 40, No. 2, February 1991, pp. 154-166;

Respectfully submitted,

Date: December 14, 2001

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